

Notice of References Cited	Application/Control No. 10/734,198	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Adeel Haroon	Art Unit 2618	Page 1 of 1

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*	A	US-6,243,563	06-2001	Nakamura, Taisuke	455/78
*	B	US-6,987,958	01-2006	Lo et al.	455/269
*	C	US-2003/0003937	01-2003	Ohkubo et al.	455/517
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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